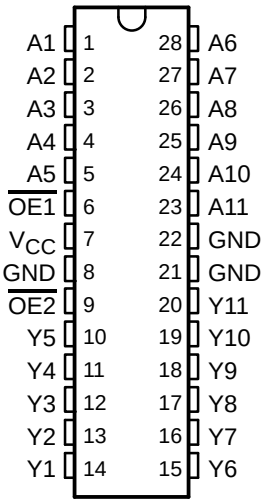
- **State-of-the-Art BiCMOS Design Significantly Reduces I_{CCZ}**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Output Ports Have Equivalent 33-Ω Series Resistors, So No External Resistors Are Required**
- **Packaged in Plastic Small-Outline Package**

DW PACKAGE
(TOP VIEW)



description

The SN74BCT2411 is an inverting 11-bit buffer/line driver specifically designed to drive MOS DRAMs of up to 4 megabits. It is also suitable for use with wide data paths or buses carrying parity. The outputs, which are designed to source 1 mA and sink 12 mA, include 33-Ω series resistors to reduce overshoot and undershoot.

The output-enable ($\overline{OE1}$ and $\overline{OE2}$) inputs are routed internally to a two-input AND gate with active-low inputs. When both $\overline{OE1}$ and $\overline{OE2}$ are low, the Y outputs are active (high or low logic level). When either $\overline{OE1}$ or $\overline{OE2}$ is high, the Y outputs are in the high-impedance state.

The multiple ground pins of the SN774BCT2411 reduce switching noise for more reliable system operation.

The SN74BCT2411 is characterized for operation from 0°C to 70°C.

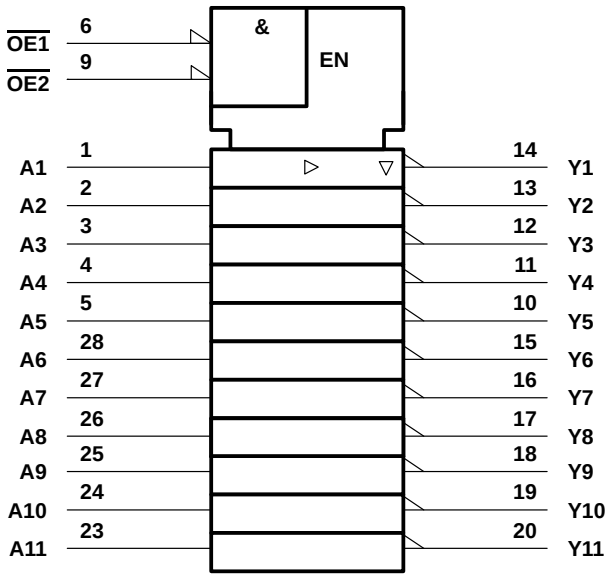
FUNCTION TABLE

INPUTS			OUTPUT
$\overline{OE1}$	$\overline{OE2}$	A	Y
L	L	L	H
L	L	H	L
X	H	X	Z
H	X	X	Z

PRODUCT PREVIEW

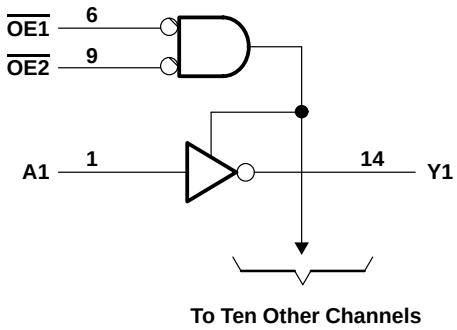
PRODUCT PREVIEW

logic symbol†

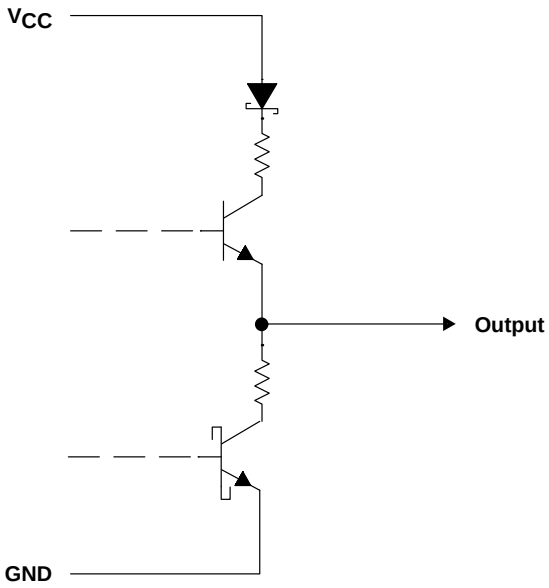


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



schematic of each output



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} . . . . . –0.5 V to 7 V
Input voltage range, V_I (see Note 1) . . . . . –0.5 V to 7 V
Voltage range applied to any output in the disabled or power-off state, V_O . . . . . –0.5 V to 5.5 V
Voltage range applied to any output in the high state, V_O . . . . . –0.5 V to V_{CC}
Input clamp current, I_{IK} (V_I < 0) . . . . . –30 mA
Current into any output in the low state, I_O . . . . . 60 mA
Operating free-air temperature range . . . . . 0°C to 70°C
Storage temperature range . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input negative-voltage rating may be exceeded if the input clamp-current rating is observed.

recommended operating conditions (see Note 2)

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			–18	mA
I_{OH}	High-level output current			–12	mA
I_{OL}	Low-level output current			12	mA
T_A	Operating free-air temperature	0		70	°C

NOTE 2: Unused or floating inputs must be held high or low.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		MIN	TYP‡	MAX	UNIT
V_{IK}	V_{CC} = 4.5 V,	I_I = –18 mA			–1.2	V
V_{OH}	V_{CC} = 4.5 V	I_{OH} = –3 mA	2.4	3.3		V
		I_{OH} = –12 mA	2	3.1		
V_{OL}	V_{CC} = 4.5 V,	I_{OL} = 64 mA		0.42	0.55	V
I_I	V_{CC} = 5.5 V,	V_I = 5.5 V			0.4	mA
I_{IH}	V_{CC} = 5.5 V,	V_I = 2.7 V			20	µA
I_{IL}	V_{CC} = 5.5 V,	V_I = 0.5 V			–0.6	mA
I_{OZH}	V_{CC} = 5.5 V,	V_O = 2.7 V			50	µA
I_{OZL}	V_{CC} = 5.5 V,	V_O = 0.5 V			–50	µA
I_{OS}§	V_{CC} = 5.5 V,	V_O = 0	–100		–225	mA
I_{CCL}	V_{CC} = 5.5 V,	V_O = 0			6.2	mA
I_{CCH}	V_{CC} = 5.5 V,	V_O = 0			8	mA
I_{CCZ}	V_{CC} = 5.5 V,	V_O = 0			8	mA
C_i	V_{CC} = 5 V,	V_I = 2.5 V or 0.5 V		5.5		pF
C_o	V_{CC} = 5 V,	V_O = 2.5 V or 0.5 V		7.5		pF

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

PRODUCT PREVIEW

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